



## TGD P-Channel Enhancement Mode Power MOSFET

**Description**

The TGD01P30K uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. It can be used in a wide variety of applications. It is ESD protected.

**General Features**

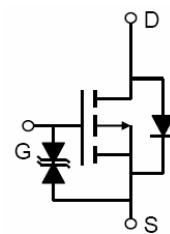
- $V_{DS} = -100V, I_D = -30A$
- $R_{DS(ON)} < 58m\Omega @ V_{GS} = -10V$  (Typ:  $44m\Omega$ )
- $R_{DS(ON)} < 65m\Omega @ V_{GS} = -4.5V$  (Typ:  $48m\Omega$ )
- Super high dense cell design
- Advanced trench process technology
- Reliable and rugged
- High density cell design for ultra low On-Resistance

**Application**

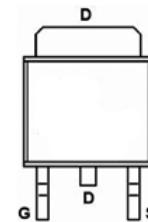
- Portable equipment and battery powered systems

**100% UIS TESTED!**

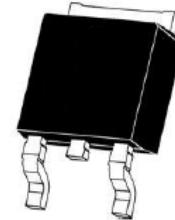
**100%  $\Delta V_{ds}$  TESTED!**



Schematic diagram



pin assignment



TO-252-2L top view

**Package Marking and Ordering Information**

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
01P30K	01P30K	TO-252-2L	-	-	-

**Absolute Maximum Ratings ( $T_c=25^\circ C$  unless otherwise noted)**

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	$V_{DS}$	-100	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Drain Current-Continuous	$I_D$	-30	A
Drain Current-Continuous( $T_c=100^\circ C$ )	$I_D (100^\circ C)$	-21	A
Pulsed Drain Current	$I_{DM}$	-150	A
Maximum Power Dissipation	$P_D$	120	W
Derating factor		0.8	W/ $^\circ C$
Operating Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 To 175	$^\circ C$

**Thermal Characteristic**

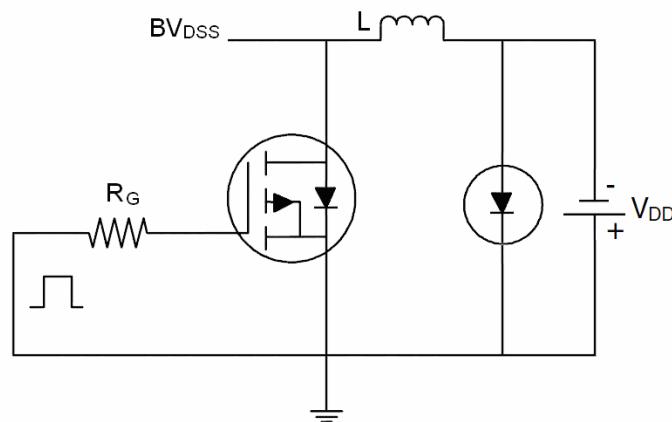
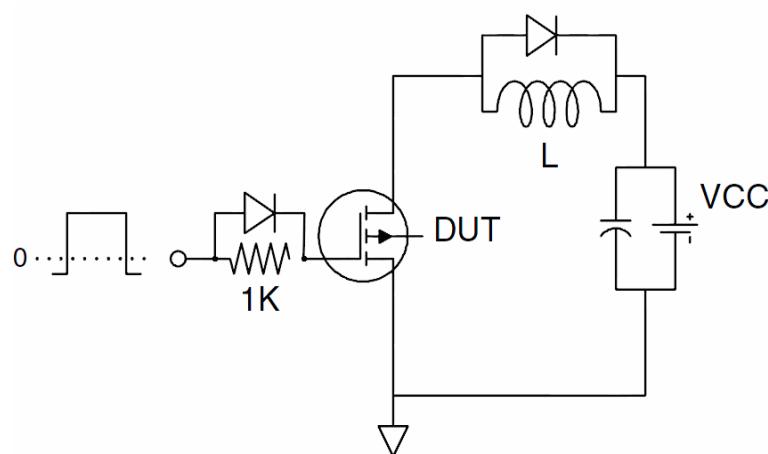
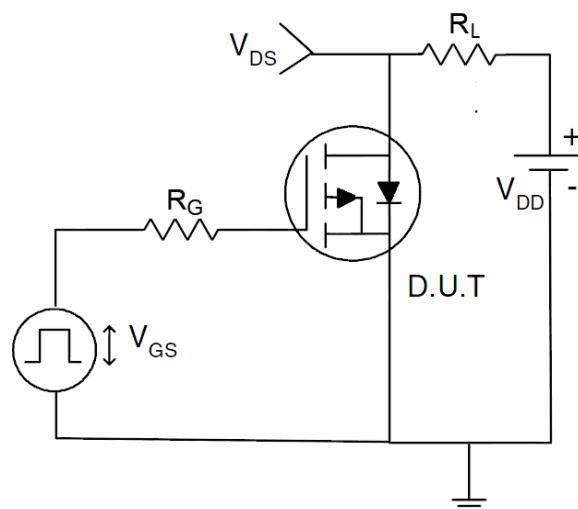
Thermal Resistance, Junction-to-Case <sup>(Note 2)</sup>	$R_{\theta Jc}$	1.25	$^\circ C/W$
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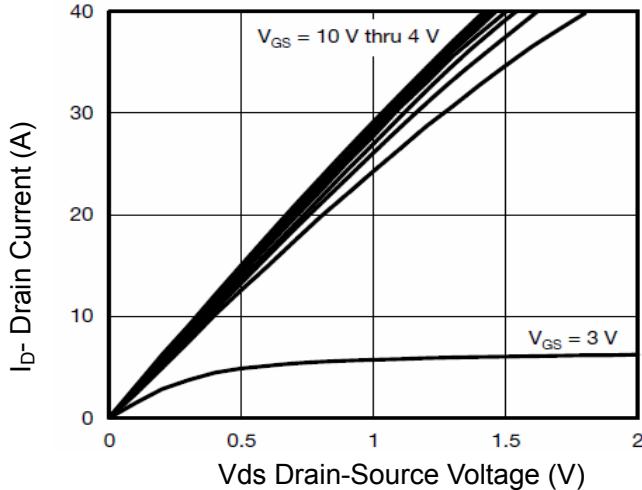
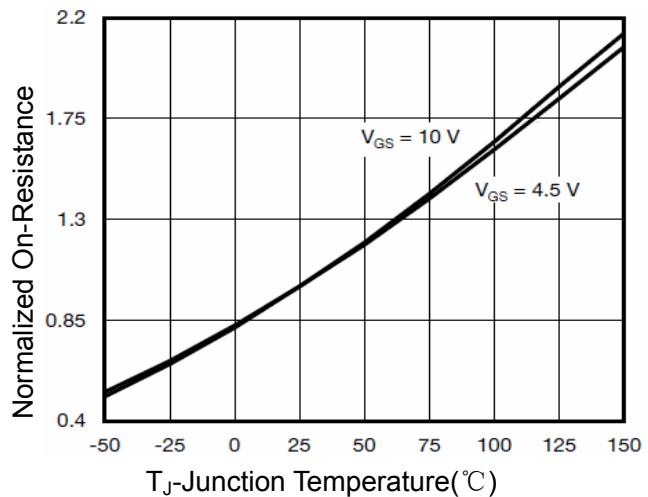
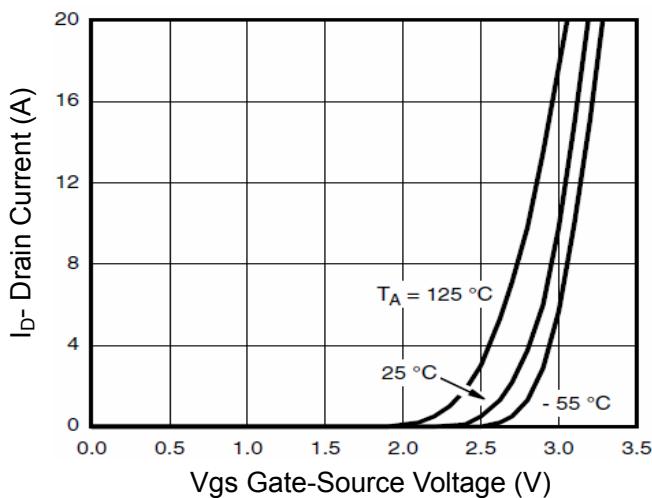
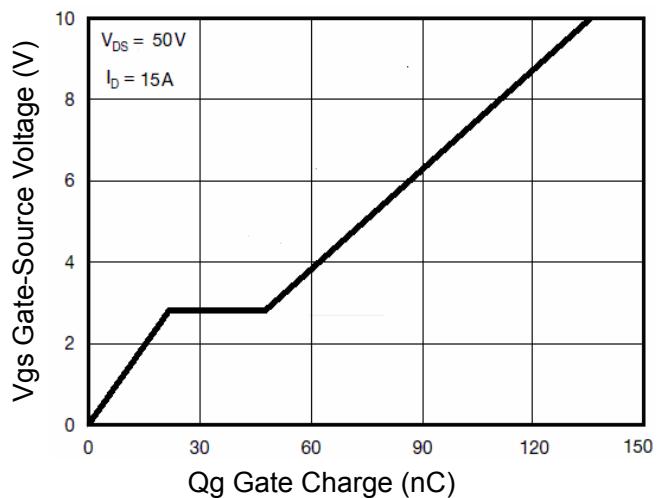
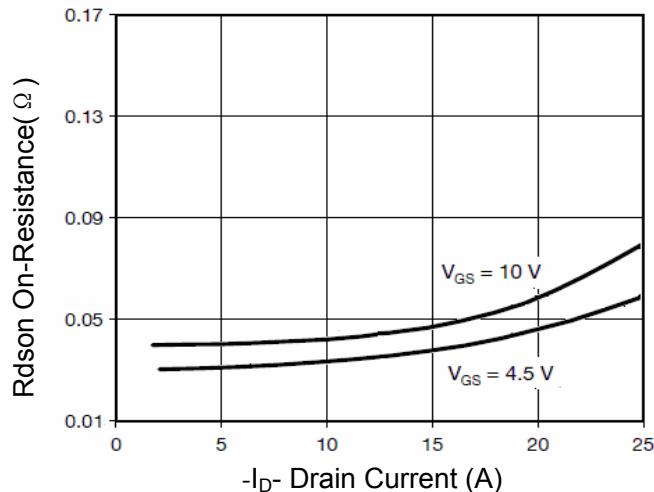
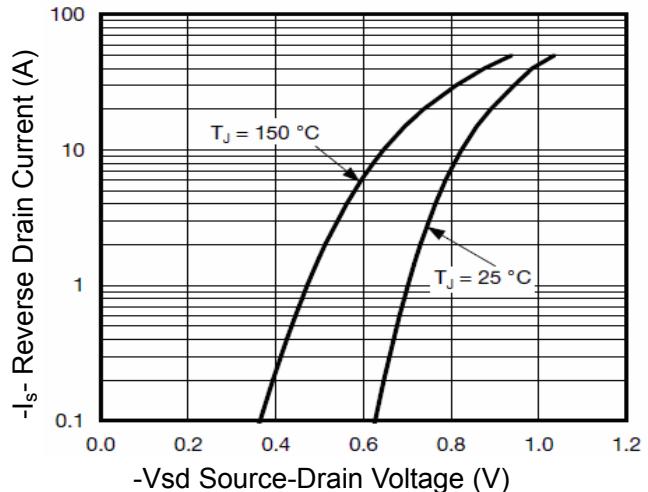
**Electrical Characteristics ( $T_C=25^\circ\text{C}$  unless otherwise noted)**

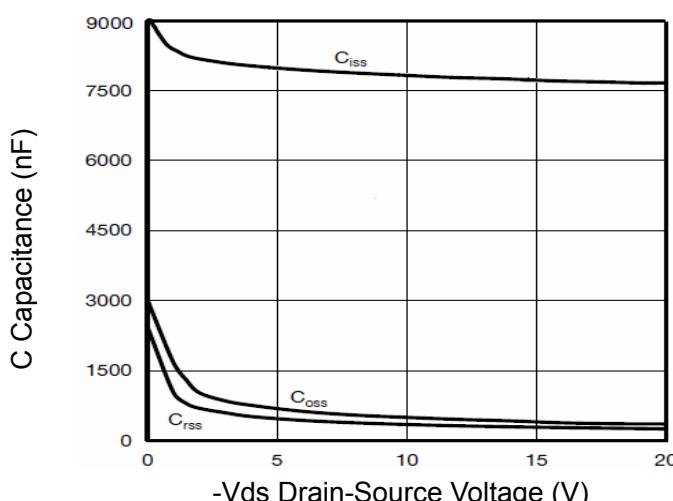
Parameter	Symbol	Condition	Min	Typ	Max	Unit
<b>Off Characteristics</b>						
Drain-Source Breakdown Voltage	$\text{BV}_{\text{DSS}}$	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_D=-250\mu\text{A}$	-100	-	-	V
Zero Gate Voltage Drain Current	$\text{I}_{\text{DSS}}$	$\text{V}_{\text{DS}}=-100\text{V}, \text{V}_{\text{GS}}=0\text{V}$	-	-	1	$\mu\text{A}$
Gate-Body Leakage Current	$\text{I}_{\text{GSS}}$	$\text{V}_{\text{GS}}=\pm20\text{V}, \text{V}_{\text{DS}}=0\text{V}$	-	-	$\pm10$	$\mu\text{A}$
<b>On Characteristics</b> <sup>(Note 3)</sup>						
Gate Threshold Voltage	$\text{V}_{\text{GS}(\text{th})}$	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_D=-250\mu\text{A}$	-1.5	-1.9	-2.5	V
Drain-Source On-State Resistance	$\text{R}_{\text{DS}(\text{ON})}$	$\text{V}_{\text{GS}}=-10\text{V}, \text{I}_D=-15\text{A}$	-	44	58	$\text{m}\Omega$
		$\text{V}_{\text{GS}}=-4.5\text{V}, \text{I}_D=-15\text{A}$	-	48	65	$\text{m}\Omega$
Forward Transconductance	$\text{g}_{\text{FS}}$	$\text{V}_{\text{DS}}=-50\text{V}, \text{I}_D=-10\text{A}$	5	-	-	S
<b>Dynamic Characteristics</b> <sup>(Note 4)</sup>						
Input Capacitance	$\text{C}_{\text{iss}}$	$\text{V}_{\text{DS}}=-50\text{V}, \text{V}_{\text{GS}}=0\text{V}, \text{F}=1.0\text{MHz}$	-	3810	-	PF
Output Capacitance	$\text{C}_{\text{oss}}$		-	93	-	PF
Reverse Transfer Capacitance	$\text{C}_{\text{rss}}$		-	91	-	PF
<b>Switching Characteristics</b> <sup>(Note 4)</sup>						
Turn-on Delay Time	$t_{\text{d}(\text{on})}$	$\text{V}_{\text{DD}}=-50\text{V}, \text{I}_D=-15\text{A}$ $\text{V}_{\text{GS}}=-10\text{V}, \text{R}_{\text{GEN}}=9.1\Omega$	-	17	-	nS
Turn-on Rise Time	$t_r$		-	80	-	nS
Turn-Off Delay Time	$t_{\text{d}(\text{off})}$		-	45	-	nS
Turn-Off Fall Time	$t_f$		-	65	-	nS
Total Gate Charge	$\text{Q}_g$	$\text{V}_{\text{DS}}=-50\text{V}, \text{I}_D=-15\text{A}, \text{V}_{\text{GS}}=-10\text{V}$	-	136	-	nC
Gate-Source Charge	$\text{Q}_{\text{gs}}$		-	22	-	nC
Gate-Drain Charge	$\text{Q}_{\text{gd}}$		-	26	-	nC
<b>Drain-Source Diode Characteristics</b>						
Diode Forward Voltage <sup>(Note 3)</sup>	$\text{V}_{\text{SD}}$	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_s=-10\text{A}$	-	-	-1.2	V
Diode Forward Current <sup>(Note 2)</sup>	$\text{I}_s$	-	-	-	-30	A
Reverse Recovery Time	$t_{\text{rr}}$	$\text{TJ} = 25^\circ\text{C}, \text{IF} = -15\text{A}$ $\text{di/dt} = 100\text{A}/\mu\text{s}$ <sup>(Note 3)</sup>	-	90	-	nS
Reverse Recovery Charge	$\text{Q}_{\text{rr}}$		-	70	-	nC
Forward Turn-On Time	$t_{\text{ton}}$	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

**Notes:**

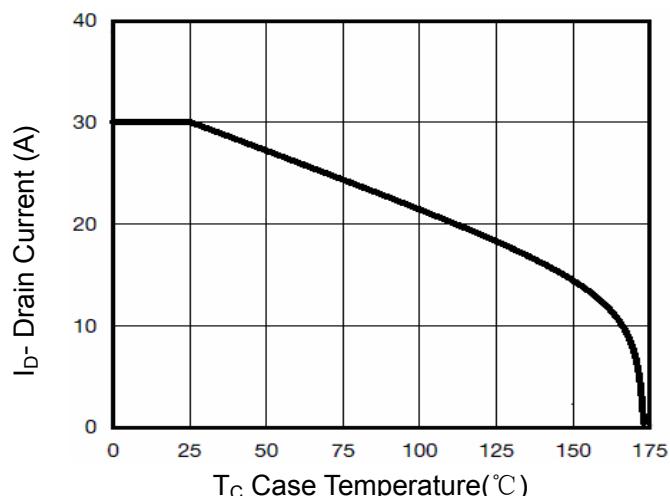
1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. Surface Mounted on FR4 Board,  $t \leq 10$  sec.
3. Pulse Test: Pulse Width  $\leq 300\mu\text{s}$ , Duty Cycle  $\leq 2\%$ .
4. Guaranteed by design, not subject to production

**Test Circuit**
**1) E<sub>AS</sub> Test Circuit**

**2) Gate Charge Test Circuit**

**3) Switch Time Test Circuit**


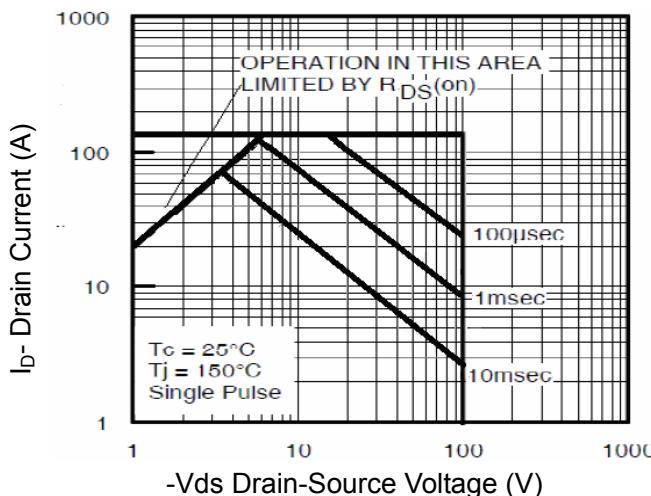
**Typical Electrical and Thermal Characteristics (Curves)**

**Figure 1 Output Characteristics**

**Figure 4 Rdson-JunctionTemperature**

**Figure 2 Transfer Characteristics**

**Figure 5 Gate Charge**

**Figure 3 Rdson- Drain Current**

**Figure 6 Source- Drain Diode Forward**



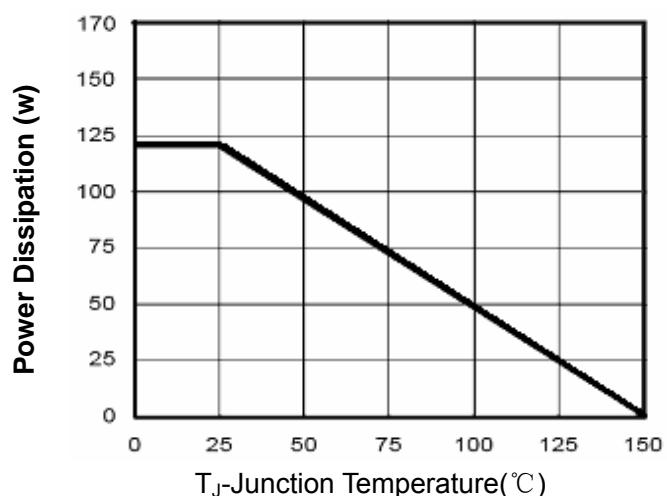
**Figure 7 Capacitance vs Vds**



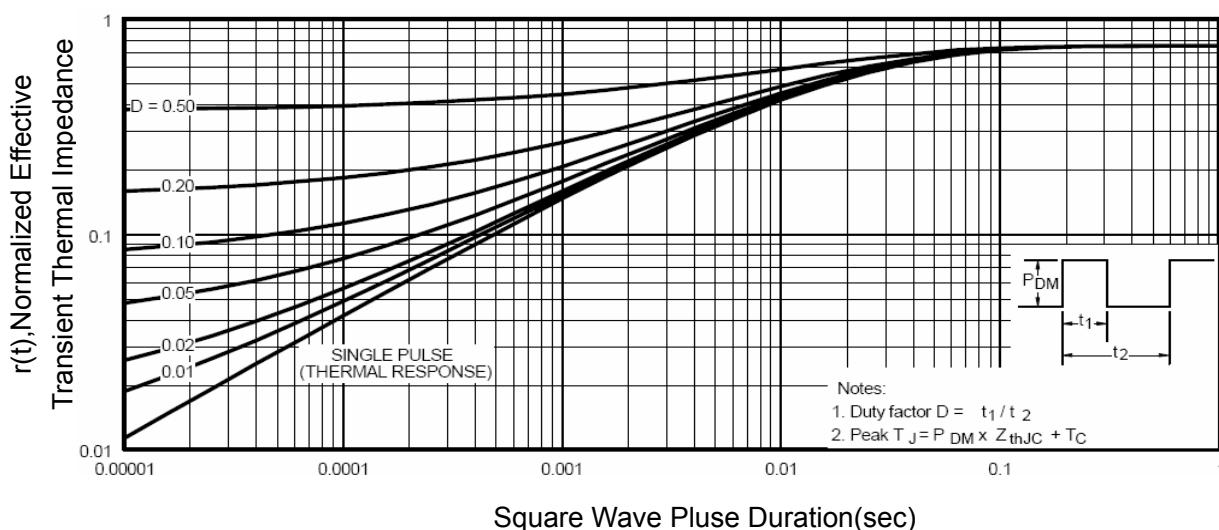
**Figure 9 Drain Current vs Case Temperature**



**Figure 8 Safe Operation Area**



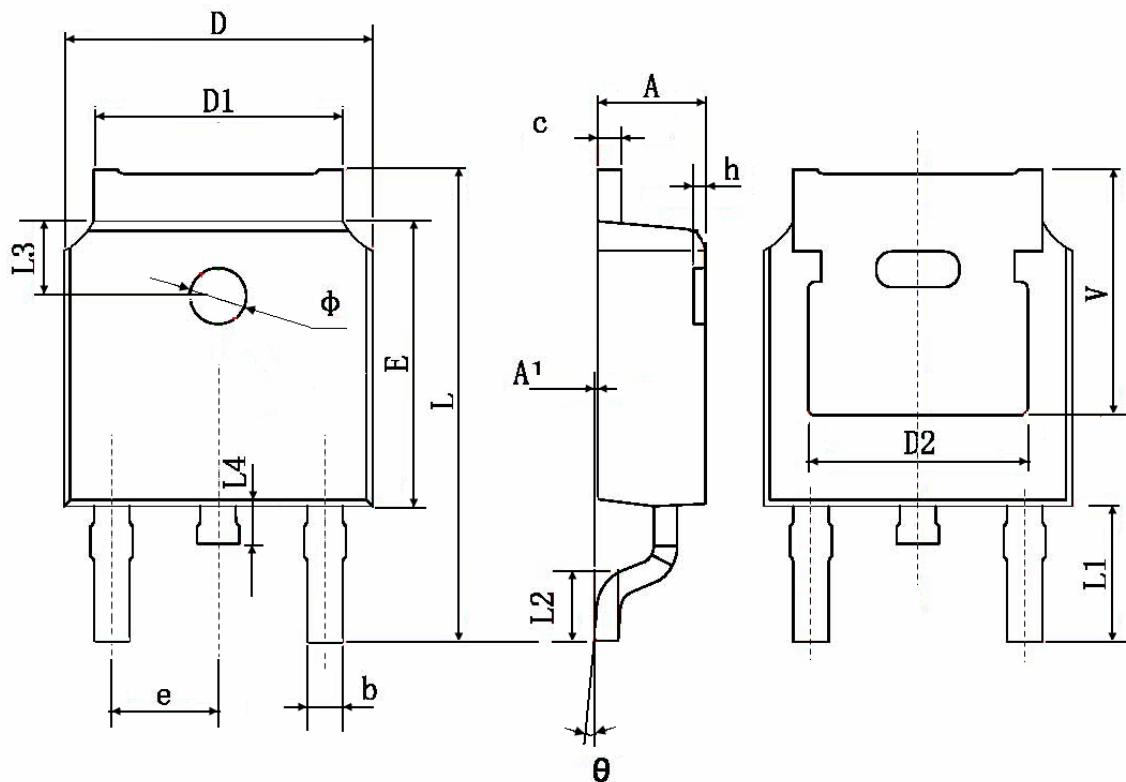
**Figure 10 Power De-rating**



**Figure 11 Normalized Maximum Transient Thermal Impedance**



## TO-252 Package Information



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	2.200	2.400	0.087	0.094
A1	0.000	0.127	0.000	0.005
b	0.660	0.860	0.026	0.034
c	0.460	0.580	0.018	0.023
D	6.500	6.700	0.256	0.264
D1	5.100	5.460	0.201	0.215
D2	4.830TYP.		0.190 TYP.	
E	6.000	6.200	0.236	0.244
e	2.186	2.386	0.086	0.094
L	9.800	10.400	0.386	0.409
L1	2.900 TYP.		0.114 TYP.	
L2	1.400	1.700	0.055	0.067
L3	1.600 TYP.		0.063 TYP.	
L4	0.600	1.000	0.024	0.039
Φ	1.100	1.300	0.043	0.051
θ	0°	8°	0°	8°
h	0.000	0.300	0.000	0.012
V	5.350 TYP.		0.211 TYP.	